

Materials List for:

Characterization of Nanocrystal Size Distribution using Raman Spectroscopy with a Multi-particle Phonon Confinement Model

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Materials

Name	Company	Catalog Number	Comments
Raman Spectroscopy	Renishaw	In Via	Equipped with 514 nm Ar ion laser
Wire 3.0	Renishaw		Raman spectroscopy record tool
Mathematica	Wolfram		For fitting function and size determination
Substrate			Plexiglass (to avoid signal coincidence with Si-NCs)
Si wafer			Reference to Si-NC peak position
Photoluminescence Spectroscopy			334 nm Ar laser. For optical size distribution.
Transmission Electron Microscopy			Beam intensity 300 kV. For nanocrystal size and morphology determination.